



LIST OF PUBLICATIONS CITED BY APPLICANT			<u>Atty. Docket No.</u> 0553-0184.01	<u>Serial No.</u> 10/642,803		
			<u>Applicant</u> Shunpei YAMAZAKI et al			
			<u>Filing Date</u> August 18, 2003	<u>Group</u>		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
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	5,576,857	11/09/96	Takemura	359	59	03/30/93
	5,595,638	01/21/97	Konuma et al	205	96	03/10/95
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<p>AI OIPE SEP 11 2003 PATENT & TRADEMARK OFFICE</p>	JP 6-160878	06/07/94	Hitachi Ltd.	X		09/10/93
	JP 7-130652	05/19/95	Semiconductor	X		10/29/93
	JP 9-211477	08/15/97	Energy Lab Co. Ltd.	X		01/31/96
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SHIMOKAWA, R. et al, "Characterization of High-Efficiency Cast-Si Solar Cell
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no. 5, pp. 751-758, May (1988).

Not available to examiner. AS 12/22/04

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